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Raman imaging of defects in single-layer and multi-layer graphene PUBUDU GALWADUGE, JOSPEH LAMBERT, ROBERTO RAMOS, Drexel University — Graphene is a two-dimensional crystal that has caught the attention of many research groups around the world. Raman spectroscopy is commonly used to identify single and multi-layer graphene. We report on the use of Raman imaging as a tool for studying structural defects in graphene. We focus on identifying defects and observing defect evolution using this technique.

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